Search	N	o	tes
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Application/Control No.	Applicant(s)/Patent under Reexamination
10/005,224	BASKO ET AL.
Examiner	Art Unit
Hanh B. Thai	2163

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SEARCHED				
Class	Subclass	Date	Examiner	
707	1-10	4/6/2006	нт	
707	203	4/6/2006	нт	
709	223-224	4/6/2006	нт	
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INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
1, 203	4/6/2006	нт	
223-224	4/6/2006	НТ	
	Subclass 1, 203	Subclass Date 1, 203 4/6/2006	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East search (text search-updated)	4/6/2006	нт	
Consulted: Kindred, Alford (primary 707)	4/4/2006	нт	
IEEE search ACM search	4/6/2006	нт	
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